AMENDMENTS TO THE SPECIFICATION:

Please replace paragraph [0005] appearing on page 2 of the present application with the following rewritten paragraph:

--Another solution to the above mentioned problem is to use fuses for trimming passive elements. The prior Pior art teaches the method of trimming devices based upon a circuit test. In this method, a circuit is tested and then an appropriate circuit element is selected. In this case, a measurement and feedback loop is required as well as a fuse scheme. In this case Moreover, elements remaining in the circuit after fuse trimming can cause unwanted parasitic capacitance since they remain attached to the main circuit although not active.--

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